

# **2018 IEEE 19th Latin-American Test Symposium (LATS 2018)**

**Sao Paulo, Brazil  
12-14 March 2018**



**IEEE Catalog Number: CFP18LAT-POD  
ISBN: 978-1-5386-1473-0**

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IEEE Catalog Number:	CFP18LAT-POD
ISBN (Print-On-Demand):	978-1-5386-1473-0
ISBN (Online):	978-1-5386-1472-3
ISSN:	2373-0862

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**Technical Program**  
**2018 IEEE 19<sup>th</sup> Latin-American Test Symposium (LATS)**  
**Sao Paulo, Brazil**  
**12<sup>th</sup> – 14<sup>th</sup> March 2018**

**Day 1: Monday, 12<sup>th</sup> March**

**Keynote Talk**

Cognitive Computing: Design, Test, and Verification Challenges N/A  
*Kaushik Roy, Purdue University – USA*

**Session 1: Reliability Analysis in SoCs**

Reliability Evaluation on Interfacing with AXI and AXI-S on Xilinx Zynq-7000 AP-SoC 1  
*Fabio Benevenuti (UFRGS, Brazil) and Fernanda Kastensmidt (UFRGS, Brazil)*

Reliability Analysis on Case-Study Traffic Sign Convolutional Neural Network on APSoC 7  
*Israel Lopes (UFRGS, Brazil), Fabio Benevenuti (UFRGS, Brazil), Fernanda Kastensmidt, Altamiro Susin (UFRGS, Brazil) and Paolo Rech (UFRGS, Brazil)*

Processor Core Profiling for SEU Effect Analysis 13  
*Rodrigo Travessini (UFSC, Brazil), Paulo R. C. Villa (UFSC, Brazil), Fabian L. Vargas (PUCRS, Brazil) and Eduardo A. Bezerra (LIRMM Montpellier, France)*

**Session 2: Manufacturing Test and Silicon Validation**

A flexible stand-alone FPGA-based ATE for ASIC manufacturing tests 19  
*Dionisio Carvalho (USP, Brazil), Bruno Sanches (USP, Brazil), Mauricio de Carvalho (USP, Brazil) and Wilhelmus Van Noije (USP, Brazil)*

Post-Silicon Validation based on synthetic test patterns for early detection of timing anomalies 25  
*Eduardo Garcia-Espinosa (Intel, Mexico), Enrique Gonzalez-Garcia (Intel, Mexico), Omar H. Longoria Gandara (ITESO, Mexico) and Arturo Veloz Guerrero (ITESO, Mexico)*

Direct Optimization of a PCI Express Link Equalization in Industrial Post-Silicon Validation 30  
*Francisco Elias Rangel-Patino (ITESO and Intel, Mexico), Jose Ernesto Rayas-Sanchez (ITESO, Mexico), Edgar Andrei Vega-Ochoa (Intel, Mexico) and Nagib Hakim (Intel, USA)*

**Invited Talk 1**

Are Self-Driving Cars Reliable? Evaluation of Radiation-Induced Errors in GPUs for Automotive Applications N/A  
*Paolo Rech (UFRGS, Brazil)*

**Session 3: Fault Tolerant Architectures**

RTOS for Mixed Criticality applications deployed on NoC-based COTS MPSoC 36  
*Stefano Esposito (Politecnico di Torino, Italy), Serhiy Avramenko (Politecnico di Torino, Italy) and Massimo Violante (Politecnico di Torino, Italy)*

Validation of a Dynamic Checkpoint Mechanism for Apache Hadoop with Failure Scenarios 42  
*Paulo Vinicius Cardoso (UFSM, Brazil) and Patrícia Pitthan Barcelos (UFRGS, Brazil)*

A Review of Approximate Computing Techniques towards Fault Mitigation in HW/SW Systems 48  
*Alexander Aponte-Moreno (Universidad Nacional de Colombia, Colombia), Alejandro Moncada (Universidad Nacional de Colombia, Colombia), Felipe Restrepo-Calle (Universidad Nacional de Colombia, Colombia) and Cesar Pedraza (Universidad Nacional de Colombia, Colombia)*

## **Session 4: Fault Injection Strategies**

On the use of a Failure Emulator Mechanism at Nanosatellite Subsystems Integration Tests 54  
*Carlos Leandro Gomes Batista (National Institute for Space Researchers, Brazil), Eliane Martins (Campinas University, Brazil) and Maria De Fátima Mattiello-Francisco (National Institute for Space Researchers, Brazil)*

Using FPGA self-produced transients to emulate SETs for SER estimation 60  
*Fábio B. Armelin (INPE and ITA, Brazil), Lírida A. B. Naviner (Télécom ParisTech, France) and Roberto d'Amore (ITA, Brazil)*

## **Session 5: Exploring Redundancy for Fault Tolerant Systems**

Fault Masking Ratio Analysis of Majority Voters Topologies 63  
*Ingrid Oliveira (FURG, Brazil), Rafael Schvitz (FURG, Brazil) and Paulo F. Butzen (FURG, Brazil)*

Improving Approximate-TMR using Multi-Objective Optimization Genetic Algorithm 69  
*Iuri Albandes Cunha Gomes (UFRGS, Brazil), Alejandro Serrano-Cases (UFRGS, Brazil), Mayler Martins (UFRGS, Brazil), Antonio Sanchez-Clemente (UFRGS, Brazil), Sergio Cuenca (UFRGS, Brazil) and Fernanda Kastensmidt (UFRGS, Brazil)*

## **Day 2: Tuesday, 13<sup>th</sup> March**

### **Invited Talk 2**

Long-term ElectroMagnetic Robustness of Integrated Circuits N/A  
*Sonia Ben Dhia (LAAS-INSA/Toulouse, France) and Bernd Deutschmann (Technical University of Graz, Austria)*

## **Session 6: Test and Fault Tolerance in Memories**

Flexible Architecture of Memory BISTs 75  
*Reinaldo Silveira, Qadeer Qureshi and Rodrigo Zeli (NXP, Brazil)*

A Hardware-Based Approach for SEU Monitoring in SRAMs with Weak Resistive Defects 81  
*George Redivo Pinto (PUCRS, Brazil), Guilherme Cardoso Medeiros (PUCRS, Brazil), Fabian Vargas (PUCRS, Brazil) and Letícia Bolzani Poehls (PUCRS, Brazil)*

### **Poster Session 1**

Automated Design Flow for Applying Triple Modular Redundancy (TMR) in Complex Digital Circuits 230  
*Luis Alberto Contreras Benites (UFRGS, Brazil) and Fernanda Lima Kastensmidt (UFRGS, Brazil)*

Towards Evolvable Hardware and Genetic Algorithm Operators to Fail Safe Systems Achievement 234  
*Gabriel Natan Silva and Ricardo Duarte (UFMG, Brazil)*

Fault-Tolerant architecture with full recovery under presence of SEU 193  
*Augusto Einsfeldt and Renato Giacomini (FEI, Brazil)*

A Novel Method of Impact and Failure Mechanism Analysis of RF-Based Fault Injection: a Frequency Response Analyzer 197  
*Ricardo Maltione (University of Campinas, Brazil), Marcelo Vilalva (University of Campinas, Brazil) and Luiz Kretly (University of Campinas, Brazil)*

Alternative Functional Verification Methodology for Low and Medium Level Designs (Applied to an AES Encryption Module) 201  
*Frank Plasencia Balabarca (PUC del Peru, Peru), Edward Mitacc Meza (PUC del Peru, Peru), Mario Raffo Jara (PUC del Peru, Peru) and Carlos Silva Cárdenas (PUC del Peru, Peru)*

Architecture of an industrial analog input designed to meet safety requirements 205  
*João Ricardo Wagner de Moraes (UFGS, Brazil), Taisy Weber (UFGS, Brazil), Guilherme Müller (UFGS, Brazil), Tiago Dall'Agnol (UFGS, Brazil), Rafael Broch Macedo (UFGS, Brazil), Elaine Pereira Lima Scartezzini (UFGS, Brazil), Roque Eduardo Dapper (UFGS, Brazil), Sérgio Luis Cechin (UFGS, Brazil) and João Cesar Netto (UFGS, Brazil)*

## **Session 7: Fault Tolerance Techniques**

- Processor Checkpoint Recovery for Transient Faults in Critical Applications 87  
*Paulo R. C. Villa (UFSC, Brazil), Rodrigo Travessini (UFSC, Brazil), Fabian Vargas (PUCRS, Brazil) and Eduardo Bezerra (LIRMM Montpellier, France)*
- Exploring the Inherent Fault Tolerance of Successive Approximation Algorithms under Laser Fault Injection 93  
*Gennaro Rodrigues (UFRGS, Brazil), Fernanda Kastensmidt (UFRGS, Brazil), Vincent Pouget (IES University of Montpellier, France) and Alberto Bosio (LIRMM University of Montpellier, France)*
- Fault Tolerant Dynamically Scheduled Processor with Partial Permanent Fault Handling 99  
*Felix Mühlbauer, Lukas Schröder and Mario Schözel (University of Potsdam, Germany)*

## **Embedded Tutorial**

- Thermal Challenges for Reliable Cyber-Physical Systems N/A  
*Zebo Peng (Linköping University, Sweden)*

## **Day 3: Wednesday, 14<sup>th</sup> March**

### **Session 8: Aging Modeling and Mitigation**

- A Metric-Guided Gate-Sizing Methodology for Aging Guardband Reduction 105  
*Andrés Felipe Gómez (INAOE, Mexico), Roberto Gomez (University of Sonora, Mexico), Victor Champac (INAOE, Mexico)*
- Ionizing Radiation Modeling in DRAM 111  
*Moritz Fieback (Delft University of Technology, The Netherlands), Mottaqiallah Taouil (Delft University of Technology, The Netherlands), Said Hamdioui (Delft University of Technology, The Netherlands) and Marco Rovatti (European Space Agency, The Netherlands)*

### **Session 9: Testing and Security of Microprocessor Cores**

- About Functionally Untestable Fault Identification in Microprocessor Cores for Safety-Critical Applications 117  
*Riccardo Cantoro (Politecnico di Torino, Italy), Andrea Firrincieli (Politecnico di Torino, Italy), Davide Piumatti (Politecnico di Torino, Italy), Marco Restifo (Politecnico di Torino, Italy), Ernesto Sanchez (Politecnico di Torino, Italy) and Matteo Sonza Reorda (Politecnico di Torino, Italy)*
- Defeating Hardware Trojan in Microprocessor Cores through Software Obfuscation 123  
*Andrea Marcelli, Ernesto Sanchez, Giovanni Squillero, Afnan Imtiaz, Paolo Monti, Muhammad Usman Jamal, Davide Pola, Alessandro Salvato, Michele Simili, Simone Machetti and Filippo Mangani (Politecnico di Torino, Italy)*

### **Session 10: Testing Techniques for Embedded Systems**

- Testing Approximate Digital Circuits: Challenges and Opportunities 129  
*Marcello Traiola (LIRMM University of Montpellier, France), Arnaud Virazel (LIRMM University of Montpellier, France), Patrick Girard (LIRMM University of Montpellier, France), Mario Barbareschi (DIETI University of Naples Federico II, Italy) and Alberto Bosio (LIRMM University of Montpellier, France)*
- Design and Test of the RT-NKE Task Scheduling Algorithm for Multicore Architectures 135  
*Renato Severo (State University of Rio Grande do Sul, Brazil), Celso Costa (State University of Rio Grande do Sul, Brazil), Adriane Parraga (State University of Rio Grande do Sul, Brazil), Debora Motta (State University of Rio Grande do Sul, Brazil), Ivan Muller (UFRGS, Brazil) and Fabian Vargas (PUCRS, Brazil)*
- Real-Time Validation of Mixed-Criticality Applications 141  
*Stefano Esposito (Politecnico di Torino, Italy), Jacopo Sini (Politecnico di Torino, Italy) and Massimo Violante (Politecnico di Torino, Italy)*

### **Session 11: Testing of Analog Systems**

- Using Short-Term Fourier Transform for Particle Detection and Recognition in a CMOS Oscillator-based Chain 147  
*Hassen Aziza, Karine Coulié, Wenceslas Rahajandraibe and Remy Vauche (Aix Marseille University, University Toulon, CNRS, IM2NP, France)*
- Exploiting Power Supply Ramp Rate for Calibrating Cell Strength in SRAM PUFs 152  
*Wendong Wang (Auburn University, USA), Adit Singh(Auburn University, USA), Ujjwal Guin (Auburn Univiersity, USA) and Abhijit Chatterjee (Georgia Institute of Technolgy, USA)*

## **Session 12: Dependable Embedded Systems**

TDevCGen: A Synthesis Toolset of HW/SW Communication Protocol Monitors from high-level Specifications 158

*Rafael Melo Macieira (UFP, SENAI Innovation Institute, Brazil) and Edna Barros (UFP, Brazil)*

Error Detection Methods For The ARINC429 Communication 164

*Marcos Silveira Santos (ITA, Brazil) and Roberto d'Amore (ITA, Brazil)*

Superimposed In-Circuit Debugging for Self-Healing FPGA Overlays 170

*Alexandra Kourfali (Ghent University, Belgium) and Dirk Stroobandt (Ghent University, Belgium)*

## **Poster Session 2**

Influence of Passive Oscillator Component Variation on OBT Sensitivity in OTAs 209

*Pablo Petrashin (Universidad Católica de Córdoba, Argentina), Tinus Stander (University of Pretoria, South Africa), Fortunato Dualibe (Université de Mons, Belgium), Luis Toledo (Universidad Católica de Córdoba, Argentina), Walter Lancioni (Universidad Católica de Córdoba, Argentina) and Carlos Vazquez (Universidad Católica de Córdoba, Argentina)*

Challenges and Emerging Solutions in Testing HBM IO & Systems 213

*Salem Abdennadher, Michael Altmann and Bin Xue (Intel Corporation, USA)*

IJTAG Compatible Analogue Embedded Instruments for MPSoC Life-time Prediction 217

*Jerrin Pathrose (University of Twente, The Netherlands), Ghazanfar Ali (University of Twente, The Netherlands) and Hans Kerkhoff (University of Twente, The Netherlands)*

Probability Aware Fault-Injection Approach for SER Estimation 221

*Fábio B. Armelin (INPE and ITA, Brazil), Lírida A. B. Naviner (Télécom ParisTech, France) and Roberto d'Amore (Télécom ParisTech, France)*

Single Event Effect: simulations and analysis on 3N163 PMOS transistor 224

*Juliano Alves de Oliveira (FEI, Brazil), Renato Camargo Giacomini (FEI, Brazil), Marco Antônio Assis de Mello (FEI, Brazil) and Marcilei Guazzelli (FEI, Brazil)*

Analysis of LEON3 systems integration for a Network-on-Chip 227

*Lucas Pereira (University of Vale do Itajai, Brazil), Douglas Melo (UFSC, Brazil), Cesar Zeferino (University of Vale do Itajai, Brazil) and Eduardo Bezerra (LIRMM Montpellier, France)*

## **PhD & Master Contests**

### **Session 13: Electrical Characterization and PV Analysis**

Time Domain Electrical Characterization in Zinc Oxide Nanoparticle Thin-Film Transistors 176

*Thales E. Becker (UFRGS, Brazil), Fábio F. Vidor (UFRGS, Brazil), Gilson I. Wirth (UFRGS, Brazil), Thorsten Meyers (University of Paderborn, Germany), Julia Reker (University of Paderborn, Germany) and Ulrich Hilleringmann (University of Paderborn, Germany)*

Impact of Process Variations on the Detectability of Resistive Short Defects: Comparative Analysis between 28nm Bulk and FD-SOI Technologies 182

*Amit Karel (LIRMM, CNRS/University of Montpellier, France), Florence Azais (LIRMM, CNRS/University of Montpellier, France), Mariane Comte (LIRMM, CNRS/University of Montpellier, France), Jean-Marc Galliere (LIRMM, CNRS/University of Montpellier, France) and Michel Renovell (LIRMM, CNRS/University of Montpellier, France)*

Influence of Temperature on Dynamic Fault Behavior Due to Resistive Defects in FinFETBased SRAMs 187

*G. Medeiros (PUCRS, Brazil), T. Copetti (UFGS, Brazil), E. Brum (PUCRS, Brazil), L. Bolzani Poehls (PUCRS, Brazil) and T. Balen (UFGS, Brazil)*